

Search Notes

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Examiner

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Reexamination

ZHENG ET AL.

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SEARCHED

Class	Subclass	Date	Examiner
708	550-553	11/7/2007	MAI

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	11/7/2007	MAI